Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination
10/722,589	COHEN ET AL.
Examiner	Art Unit
Mark W. Bockelman	3766

SEARCHED				
Class	Subclass	Date	Examiner	
607	63,4°1 45-46, 62, 148-149	2-17-06	MC	
	148-149	·		
ws	dite	12-22-06	MB	
				
			 	

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Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
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